

L Number	Hits	Search Text	DB	Time stamp
1	292	(SOC and (system near3 chip)) and (layer near2 (top bottom))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 16:38
2	138	(SOC and (system near3 chip)) and (layer near2 (top bottom)) and pad	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 16:52
3	100	(SOC and (system near3 chip)) and (layer near2 (top bottom)) and pad and (vector pattern)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 18:04
4	17	(SOC and (system near3 chip)) and (layer near2 (top bottom)) and pad and ((vector pattern) near3 (test\$4 evaluat\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 17:11
5	13	(layer near2 (top bottom)) same pad same ((vector pattern) near3 (test\$4 evaluat\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 17:18
6	2	6249893.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 17:19
7	11	6249893.URPN.	USPAT	2004/10/30 17:20
8	9	("5535164" "5617531" "5619512" "5748640" "5825785" "5954824" "5963566" "5991898" "6003142").PN.	USPAT	2004/10/30 17:21
9	2	(SOC and (system near3 chip)).ab. and (layer near2 (top bottom)) and pad and ((vector pattern) near3 test\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 18:05
10	2	(SOC and (system near3 chip)).ab. and (layer near2 (top bottom)) and ((vector pattern) near3 test\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 18:05
11	21	(SOC and (system near3 chip)).ab. and ((vector pattern) near3 test\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 18:05

-	191979	SOC	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/29 11:58
-	0	SOC and (system adj on adj chip)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/29 11:58
-	2402	SOC and (system near3 chip)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/30 16:36
-	1348	(SOC and (system near3 chip)) and (test testing tested tester evaluate evaluating evaluation evaluated)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/29 12:27
-	380	(SOC and (system near3 chip)) and (test testing tested tester evaluate evaluating evaluation evaluated) and pad	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/29 12:28
-	304	(SOC and (system near3 chip)) and (test testing tested tester evaluate evaluating evaluation evaluated) and pad and (vector pattern)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/29 12:28
-	241	(SOC and (system near3 chip)) and (test testing tested tester evaluate evaluating evaluation evaluated) and pad and (vector pattern) and layer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/29 19:58
-	2	6150861.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/29 19:58